

Search Notes

Application/Control No.

10/694,220

Examiner

Tianjie Chen

Applicant(s)/Patent under
Reexamination

KIM ET AL.

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
369	300		
	221		
	13.13		
	44.19		
	44.23		
360	126		
310	309		
720	681	8/28/2006	TJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Report	8/28/2006	TJ